# FDP4D5N10C / FDPF4D5N10C N-Channel Shielded Gate PowerTrench<sup>®</sup> MOSFET

**100 V, 128 A, 4.5 m**Ω

## Features

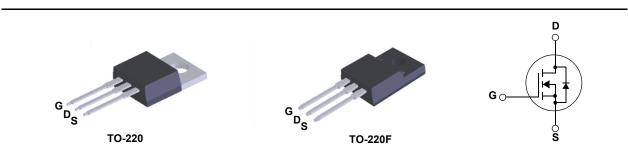
- Max  $r_{DS(on)}$  = 4.5 m $\Omega$  at V<sub>GS</sub> = 10 V, I<sub>D</sub> = 100 A
- Extremely Low Reverse Recovery Charge, Qrr
- 100% UIL Tested
- RoHS Compliant



This N-Channel MV MOSFET is produced using ON Semiconductor's advanced PowerTrench<sup>®</sup> process that incorporates Shielded Gate technology. This process has been optimized to minimize on-state resistance and yet maintain superior switching performance with best in class soft body diode.

# Applications

- Synchronous Rectification for ATX / Server / Telecom PSU
- Motor Drives and Uninterruptible Power Supplies
- Micro Solar Inverter



# MOSFET Maximum Ratings T<sub>C</sub> = 25 °C unless otherwise noted.

Symbol	Parameter		Ratings			
			FDP4D5N10C	FDPF4D5N10C	Units	
V <sub>DS</sub>	Drain to Source Voltage			100	100	V
V <sub>GS</sub>	Gate to Source Voltage			±20	±20	V
I <sub>D</sub>	Drain Current -Continuous	T <sub>C</sub> = 25°C	(Note 3)	128*	128*	А
	-Continuous	T <sub>C</sub> = 100°C	(Note 3)	91	91	
	-Pulsed		(Note 1)	512	512	
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 2)		(Note 2)	486		mJ
P <sub>D</sub>	Power Dissipation	T <sub>C</sub> = 25°C		150	37.5	w
	Power Dissipation	T <sub>A</sub> = 25°C		2.4	2.4	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction T	emperature Range		-55 to +175	-55 to +175	°C

\* Drain current limited by maximum junction temperature. Package limitation current is 120A.

### **Thermal Characteristics**

Symbol	Parameter	FDP4D5N10C	FDPF4D5N10C	Units
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	1.0	4.0	°C/W
$R_{ hetaJA}$	Thermal Resistance, Junction to Ambient	62.5	62.5	0/11

#### Package Marking and Ordering Information

Device Marking	Device	Package	Packing Mode	Quantity
FDP4D5N10C	FDP4D5N10C	TO-220	Tube	50 units
FDPF4D5N10C	FDPF4D5N10C	TO-220F	Tube	50 units

eristics rain to Source Breakdown Voltage reakdown Voltage Temperature	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0 V	100		1	
reakdown Voltage Temperature		100		1	
<b>U</b>					V
oefficient	$I_D$ = 250 $\mu$ A, referenced to 25 °C		53		mV/°C
Zero Gate Voltage Drain Current	V <sub>DS</sub> = 80 V, V <sub>GS</sub> = 0 V			1	μA
	V <sub>DS</sub> = 80 V, T <sub>J</sub> = 150°C			500	μA
ate to Source Leakage Current	$V_{GS}$ = ±20 V, $V_{DS}$ = 0 V			±100	nA
eristics					
ate to Source Threshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 310 μA	2.0	3.2	4.0	V
tatic Drain to Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 100 A		4.0	4.5	mΩ
orward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 100 A		134		S
aracteristics					
nput Capacitance			3615	5065	pF
output Capacitance			2330	3265	pF
everse Transfer Capacitance			18	35	pF
ate Resistance		0.1	1.1	2.2	Ω
haracteristics					
urn-On Delay Time			29	47	ns
lise Time	V <sub>DD</sub> = 50 V, I <sub>D</sub> = 100 A,		49	79	ns
urn-Off Delay Time	$V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$		41	66	ns
all Time			13	24	ns
otal Gate Charge	$V_{GS} = 0 V$ to 10 V		48	68	nC
ate to Source Gate Charge	v <sub>DD</sub> = 30 v,		19		nC
ate to Drain "Miller" Charge			9		nC
output Charge	V <sub>DD</sub> = 50 V, V <sub>GS</sub> = 0 V		150		nC
	ate to Source Leakage Current  eristics ate to Source Threshold Voltage atic Drain to Source On Resistance orward Transconductance  aracteristics put Capacitance utput Capacitance everse Transfer Capacitance ate Resistance  haracteristics urn-On Delay Time ise Time urn-Off Delay Time all Time btal Gate Charge ate to Source Gate Charge ate to Drain "Miller" Charge	Pro Gate Voltage Drain Current $V_{DS} = 80 \text{ V}, \text{ T}_{J} = 150^{\circ}\text{C}$ ate to Source Leakage Current $V_{GS} = \pm 20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$ Pristicsate to Source Threshold Voltage $V_{GS} = V_{DS}, \text{ I}_D = 310 \text{ µA}$ ate to Source On Resistance $V_{GS} = 10 \text{ V}, \text{ I}_D = 100 \text{ A}$ prward Transconductance $V_{DS} = 5 \text{ V}, \text{ I}_D = 100 \text{ A}$ put Capacitance $V_{DS} = 50 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ ate Resistance $V_{DS} = 50 \text{ V}, \text{ V}_{GS} = 0 \text{ V},$ te Resistance $f = 1 \text{ MHz}$ haracteristicspur-On Delay Timeise Time $V_{DD} = 50 \text{ V}, \text{ I}_D = 100 \text{ A},$ urn-Off Delay Timeall Timeotal Gate Chargeate to Source Gate Chargeate to Drain "Miller" Charge	Problem $V_{DS} = 80 \text{ V}, \text{ T}_J = 150^{\circ}\text{C}$ ate to Source Leakage Current $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$ pristicsate to Source Threshold Voltage $V_{GS} = V_{DS}, I_D = 310 \ \mu\text{A}$ 2.0ate to Source On Resistance $V_{GS} = 10 \text{ V}, I_D = 100 \text{ A}$ 2.0pristics $V_{GS} = 10 \text{ V}, I_D = 100 \text{ A}$ 2.0aracteristics $V_{DS} = 5 \text{ V}, I_D = 100 \text{ A}$ 2.0put Capacitance $V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, I_D = 100 \text{ A}$ 2.0everse Transfer Capacitance $I = 1 \text{ MHz}$ 2.0ate Resistance0.10.1haracteristics0.1pur-On Delay Time $V_{OD} = 50 \text{ V}, I_D = 100 \text{ A}, I_D = 100  A$	Pro Gate Voltage Drain Current $V_{DS} = 80 \text{ V}, \text{ T}_{J} = 150^{\circ}\text{C}$ Image: constraint of the state of the s	$\begin{array}{c c c c c c c c c c c c c c c c c c c $

Notes:

Q<sub>rr</sub>

1. Pulsed Id please refer to Figure "Forward Bias Safe Operating Area" for more details.

Reverse Recovery Charge

2. E<sub>AS</sub> of 486 mJ is based on starting T<sub>J</sub> = 25 °C, L = 3 mH, I<sub>AS</sub> = 18 A, V<sub>DD</sub> = 100 V, V<sub>GS</sub> = 10 V. 100% test at L = 0.1 mH, I<sub>AS</sub> = 58 A.

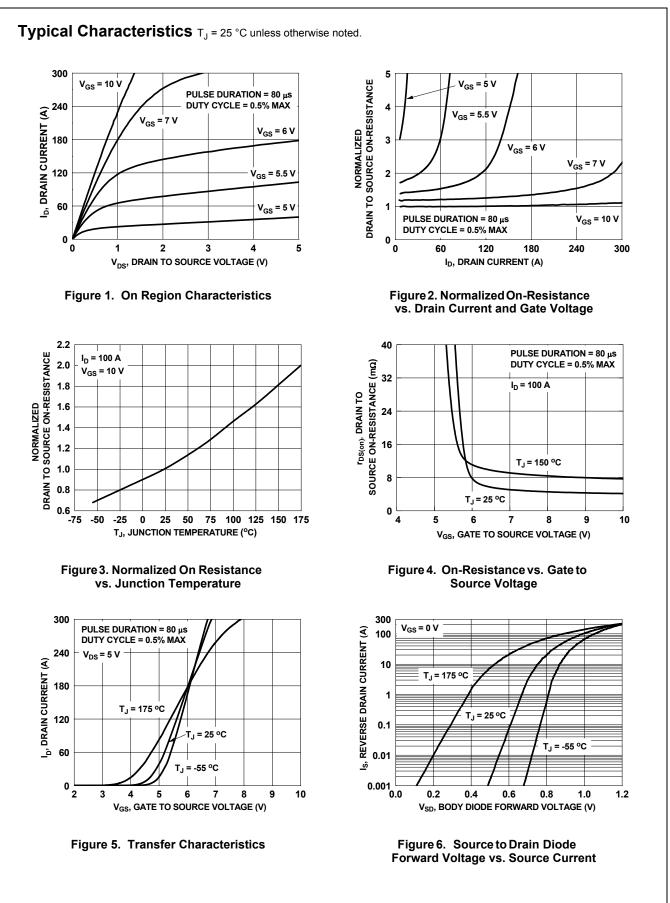
3. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

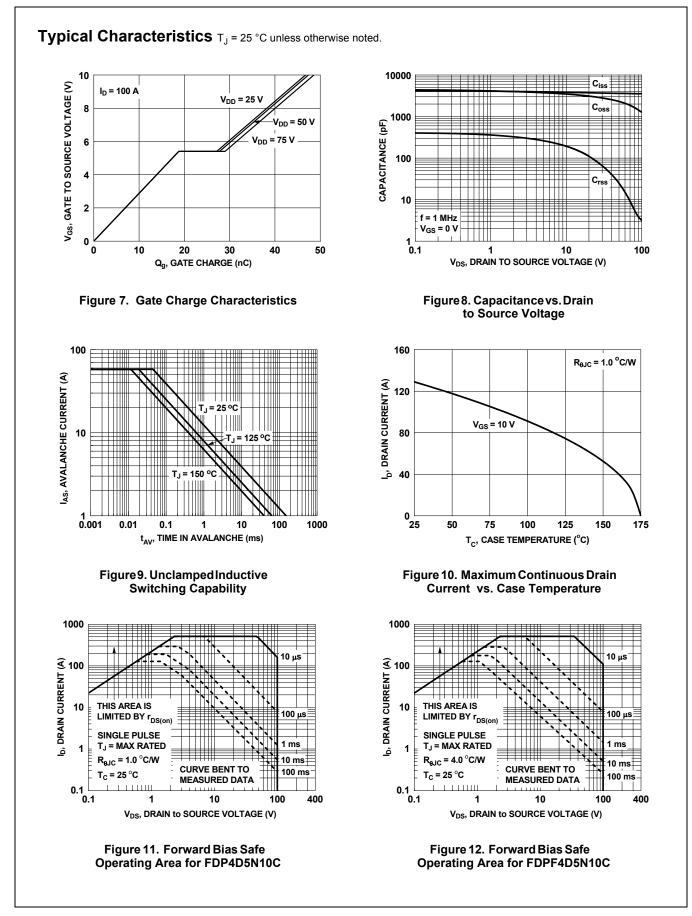
 $I_F = 100 \text{ A}, dI_F/dt = 300 \text{ A}/\mu\text{s}$ 

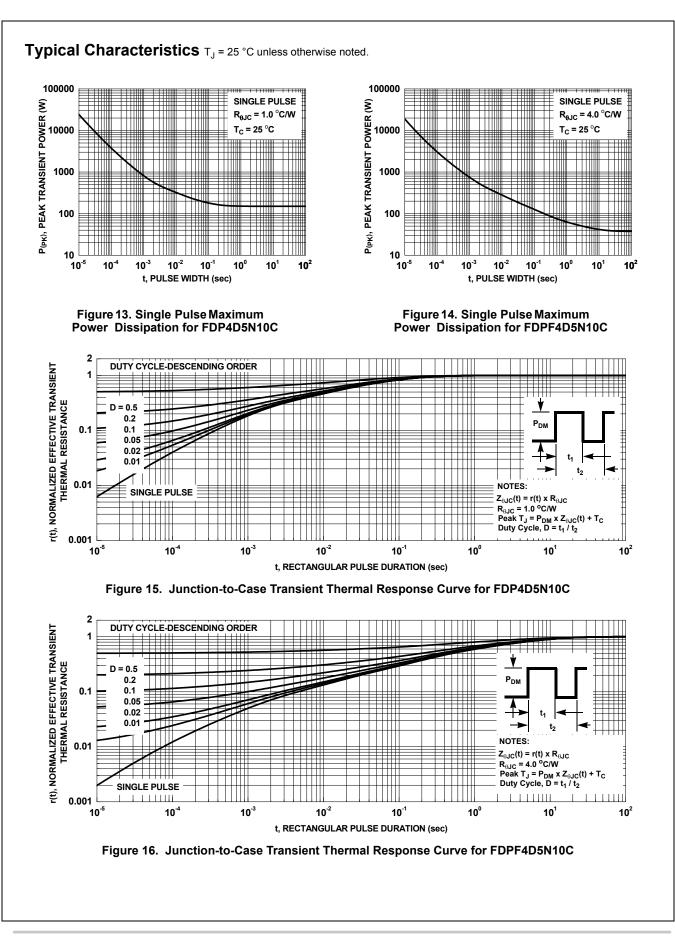
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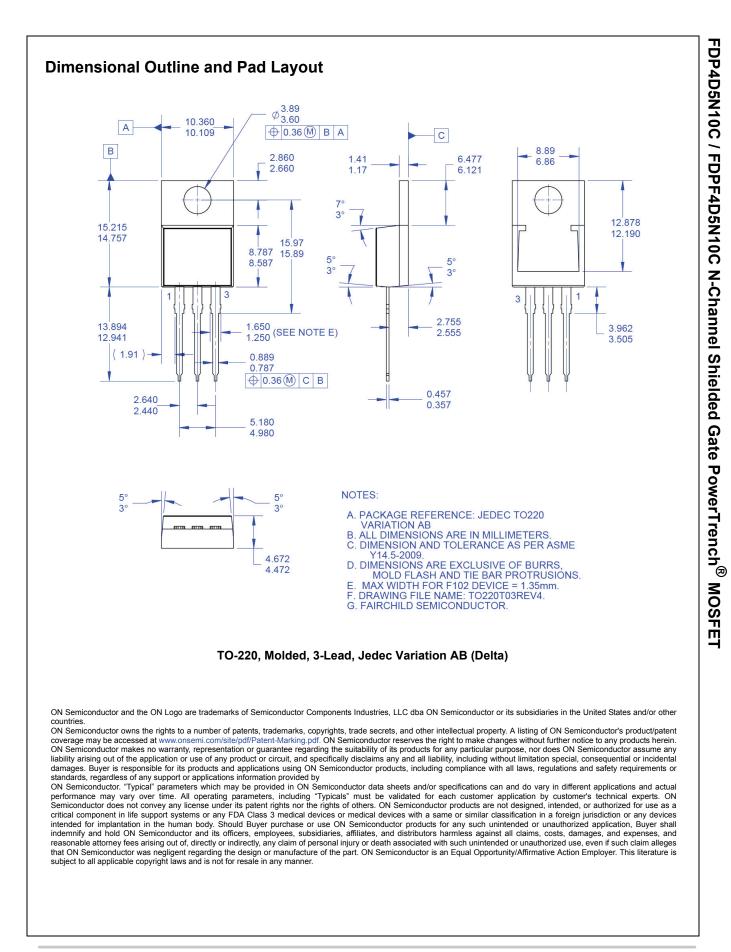
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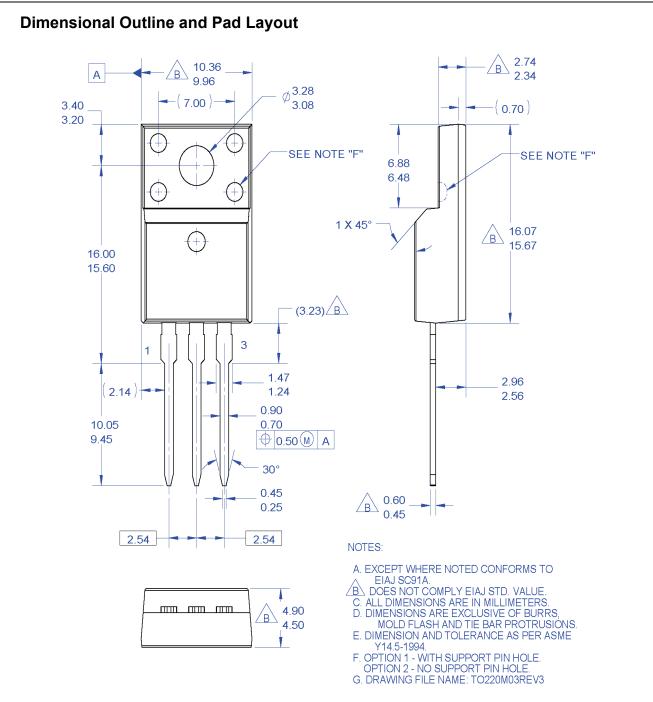
nC











#### TO220, Molded, 3-Lead, Full Pack, EIAJ SC91, Straight Lead

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